Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10661225	NGUYEN ET AL.
Examiner	Art Unit
Nguyen, Hiep	2816

SEARCHED					
Class	Subclass	Date	Examiner		
327	175, 18, 20, 26	01-25-07	Hn		

SEARCH NOTES					
	Search Notes	Date	Examiner		
EAST		09-20-07	Hn		

INTERFERENCE SEARCH						
Class	Subclass	Date	Examiner			
327	171-176	09-20-07	Hn			